

**Notice of References Cited**

Application/Control No.

10/811,541

Applicant(s)/Patent Under  
Reexamination  
UTHE ET AL.

Examiner

William Wong

Art Unit

2178

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0025812 A1	02-2003	Slatter, David Neil	348/240.2
*	B	US-6,341,183 B1	01-2002	Goldberg, Kenneth A.	382/276
*	C	US-6,029,195 A	02-2000	Herz, Frederick S. M.	725/116
*	D	US-6,084,598 A	07-2000	Chekerylla, James	345/441
*	E	US-6,249,290 B1	06-2001	Herndon et al.	345/660
*	F	US-2001/0039579 A1	11-2001	TRCKA et al.	709/224
*	G	US-2002/0044696 A1	04-2002	Sirohey et al.	382/240
*	H	US-2002/0118214 A1	08-2002	Card et al.	345/619
*	I	US-2003/0063094 A1	04-2003	Smith, Randall B.	345/581
*	J	US-2005/0197763 A1	09-2005	Robbins et al.	701/200
*	K	US-2005/0195154 A1	09-2005	Robbins et al.	345/156
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.